T-Type, Neutral Point Clamp Module

This high-density, integrated power module combines high-performance IGBTs with rugged anti-parallel diodes for sine wave inverter applications.

Features

- Extremely Efficient Trench IGBT with Fieldstop Technology
- Module Design Offers High Power Density
- Low Inductive Layout
- Q0PACK Package with Press-Fit Pins

Typical Applications

- Solar Inverters
- Uninterruptable Power Supplies

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
BRIDGE IGBT			

Collector-emitter voltage	V _{CES}	1200	V	
Collector current $T_h = 80^{\circ}C$	۱ _C	65	А	
Pulsed Collector Current, $\mathrm{T}_{\mathrm{pulse}}$ Limited by $\mathrm{T}_{\mathrm{jmax}}$	I _{CM}	260	A	
Gate-emitter voltage	V_{GE}	±20	V	
$\begin{array}{l} \mbox{Power Dissapation per IGBT} \\ \mbox{T}_{j} = \mbox{T}_{jmax} & \mbox{T}_{h} = 80^{\circ}\mbox{C} \end{array}$	P _{total}	146	W	
Short Circuit Withstand Time V _{GE} = 15 V, V _{CE} = 600 V, T _J \leq 150°C	T _{SC}	10	μs	

NEUTRAL POINT IGBT

Collector-emitter voltage (Bridge)	V _{CES}	600	V
Collector current @ $T_h = 80^{\circ}C$	Ι _C	59	А
Pulsed Collector Current, T_{pulse} Limited by T_{jmax}	I _{CM}	235	A
Gate-emitter voltage	V _{GE}	±20	V
$\begin{array}{l} \mbox{Power Dissapation per IGBT} \\ \mbox{T}_{j} = \mbox{T}_{jmax} & \mbox{T}_{h} = 80^{\circ}\mbox{C} \end{array}$	P _{total}	66	W
Short Circuit Withstand Time V_{GE} = 15 V, V_{CE} = 400 V, T_J \leq 150°C	T _{SC}	5	μs

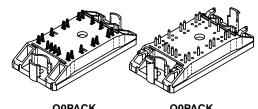
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



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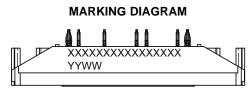
80 A, 1200 V (Bridge) 50 A, 600 V (Neutral Point Clamp) T – Type Neutral Point Clamp



Q0PACK CASE 180AA

Q0PACK CASE 180AB

SCHEMATIC 20 L11 19 15,16 15,16 10,11 10,11 10,11 10,11 10,11 10,11 10,11 10,11 10,11 10,11 10,11 10,16 10,17 1



YYWW = Year and Work Week Code

ORDERING INFORMATION

See detailed ordering and shipping information in the dimensions section on page 13 of this data sheet.

PIN ASSIGNMENTS 15 16 B B 8 B 12 13 14 17 18 **=** 11 19 📼 **=** 10 **9** 20 📼 **B** 8 76 5 4 3 2 1 88 e e 88

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
BRIDGE DIODE			
Peak Repetitive Voltage	V _{RRM}	1200	V
Forward Current, DC @ $T_C = 80^{\circ}C$	١ _F	41	А
Power Dissipation per Diode $T_j = T_{jmax}$ $T_h = 80^{\circ}C$	P _{total}	69	W
Nonrepetitive Peak Surge Current (Surge applied at rated load conditions halfwave, single phase, 60 Hz)	I _{FSM}	300	A
I ² t – value (Surge applied at rated load conditions halfwave, single phase, 60 Hz)	l ² t	373.5	A ² s
NEUTRAL POINT DIODE			
Diode peak repetitive voltage	V _{RRM}	600	V
Forward Current, DC @ $T_h = 80^{\circ}C$	١ _F	36	А
Power Dissipation per Diode $T_j = T_{jmax}$ $T_h = 80^{\circ}C$	P _{total}	51	W
Nonrepetitive Peak Surge Current (Surge applied at rated load conditions halfwave, single phase, 60 Hz)	I _{FSM}	500	A
l ² t – value (Surge applied at rated load conditions halfwave, single phase, 60 Hz)	l ² t	1037.5	A ² s

THERMAL & SAFETY CHARACTERISTICS

Rating	Symbol	Value	Unit
Maximum junction temperature range IGBT Diode	TJ	175 175	°C
Storage temperature range	T _{stg}	-40 to 150	°C
Operating Temperature under Switching conditions	T _{VJ OP}	-40 to 150	°C
Isolation test voltage, t = 1 min, 60 Hz	V _{is}	2500	Vac
Creepage distance		12.7	mm
Clearance		12.7	mm

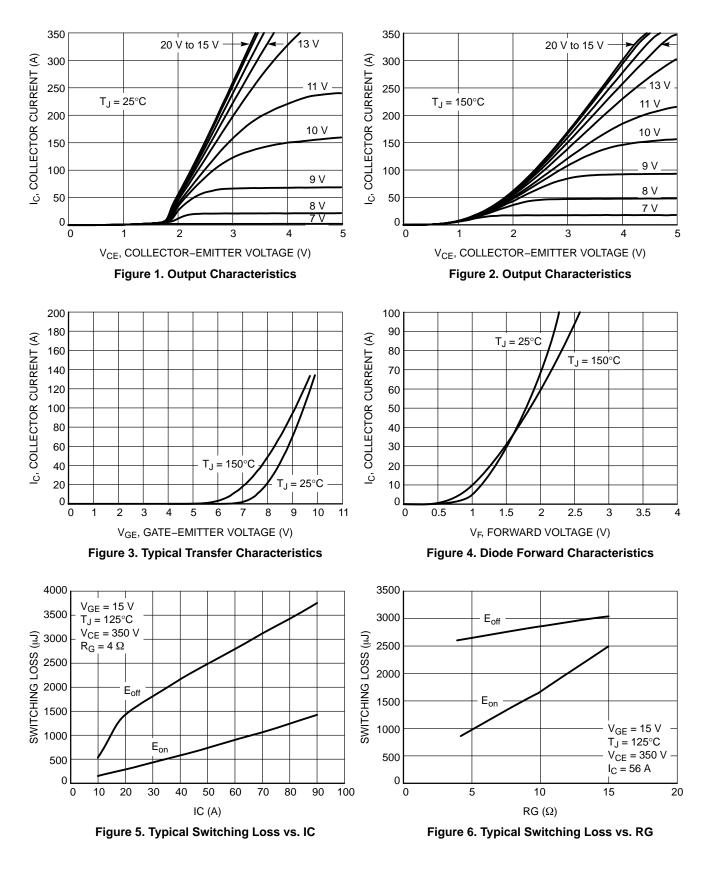
ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

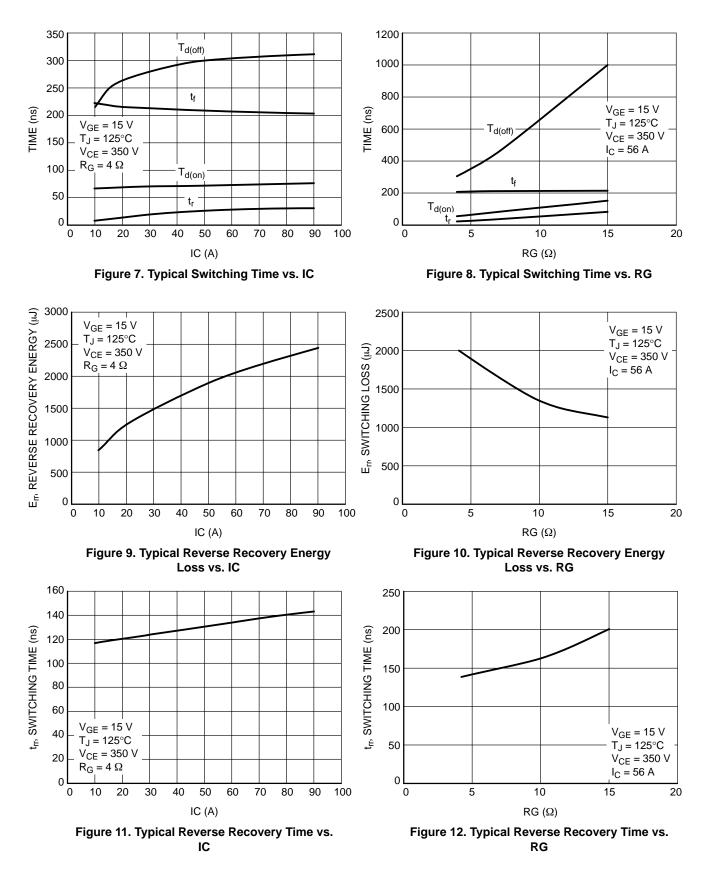
Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
HALF BRIDGE IGBT CHARACTERIS	STICS			•		
Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}, \text{ I}_{C} = 80 \text{ A}, \text{ T}_{J} = 25^{\circ}\text{C}$ $V_{GE} = 15 \text{ V}, \text{ I}_{C} = 80 \text{ A}, \text{ T}_{J} = 150^{\circ}\text{C}$	V _{CE(sat)}	1.7	2.17 2.20	2.7	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_C = 1.5 \text{ mA}$	V _{GE(TH)}	5.0	6.0	6.5	V
Collector-emitter cutoff current	V _{GE} = 0 V, V _{CE} = 1200 V	I _{CES}	_	-	200	μΑ
Gate leakage current	$V_{GE} = 20 \text{ V}, \text{ V}_{CE} = 0 \text{ V}$	I _{GES}	-	-	1.2	μΑ
Turn–on delay time	T _j = 25°C	t _{d(on)}	-	35	-	ns
Rise time	$V_{CE} = 350 \text{ V}, \text{ I}_{C} = 56 \text{ A}$	t _r	-	28	-	
Turn-off delay time	V_{GE} = ±15 V, R _G = 4 Ω	t _{d(off)}	-	280	-	
Fall time		t _f	-	28	-	
Turn on switching loss		E _{on}	_	0.670	-	mJ
Turn off switching loss		E _{off}	-	1.3	-	
Turn–on delay time	T _i = 150°C	t _{d(on)}	-	80	-	ns
Rise time	$V_{CE} = 350 \text{ V}, \text{ I}_{C} = 56 \text{ A}$	t _r	-	30	-	
Turn–off delay time	V_{GE} = ±15 V, R _G = 4 Ω	t _{d(off)}	-	320	-	
Fall time		t _f	-	230	-	
Turn on switching loss		E _{on}	_	0.975	_	mJ
Turn off switching loss		E _{off}	-	3.00	-	
Input capacitance	V _{CE} =20 V. V _{GE} = 0 V. f = 10 KHz	C _{ies}	-	19940	-	pF
Output capacitance		C _{oes}	_	592	_	
Reverse transfer capacitance		C _{res}	-	383	-	
Gate charge total	V_{CE} = 960 V, I _C = 40 A, V _{GE} = ±15 V	Qg	-	840	-	nC
Thermal Resistance, chip-to-heatsink	Thermal grease thickness \leq 50 μm λ = 1 W/mK	R _{θJH}		0.65		°C/W
HALF BRIDGE DIODE CHARACTER	ISTICS			•		
Forward voltage	$V_{GE} = 0 \text{ V}, I_F = 50 \text{ A}, T_J = 25^{\circ}\text{C}$ $V_{GE} = 0 \text{ V}, I_F = 50 \text{ A}, T_j = 150^{\circ}\text{C}$	V _F	-	1.81 1.90	2.4 -	V
Reverse recovery time	T _i = 25°C	t _{rr}	_	0.12	_	μS
Reverse recovery charge	$V_{CE} = 350 \text{ V}, I_{C} = 56 \text{ A}$	Q _{rr}	_	4.7	_	μC
Peak reverse recovery current	V_{GE} = ±15 V, R _G = 4 Ω	I _{rrm}	_	135	_	А
Peak rate of fall of recovery current		di/dt _{max}	_	7200	_	A/μs
Reverse recovery energy		Err	_	1.37	_	mJ
Reverse recovery time	T _i = 150°C	t _{rr}	_	0.14	-	μs
Reverse recovery charge	$V_{CE} = 350 \text{ V}, \text{ I}_{C} = 56 \text{ A}$	Q _{rr}	_	7.65	_	μC
Peak reverse recovery current	V_{GE} = ±15 V, R _G = 4 Ω	I _{rrm}	_	138	_	А
Peak rate of fall of recovery current		di/dt _{max}	_	4900	_	A/μs
Reverse recovery energy		Err	-	2.15	-	mJ
Thermal Resistance, chip-to-heatsink	Thermal grease thickness \leq 50 μ m λ = 1 W/mK	$R_{ hetaJH}$		1.38		°C/W
NEUTRAL POINT CLAMP IGBT CHA		<u> </u>		-	-	<u> </u>
Collector-emitter saturation voltage	V_{GE} = 15 V, I _C = 30 A, T _J = 25°C V _{GE} = 15 V, I _C = 30 A, T _J = 150°C	V _{CE(sat)}	1.1	1.3 1.3	1.6	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_C = 1.2 \text{ mA}$	V _{GE(TH)}	5.0	5.7	6.5	V
Collector-emitter cutoff current	V _{GE} = 0 V, V _{CE} = 600 V	I _{CES}	-	-	100	μA
Gate leakage current	V _{GE} = 20 V, V _{CE} = 0 V	I _{GES}	_	-	0.60	μA

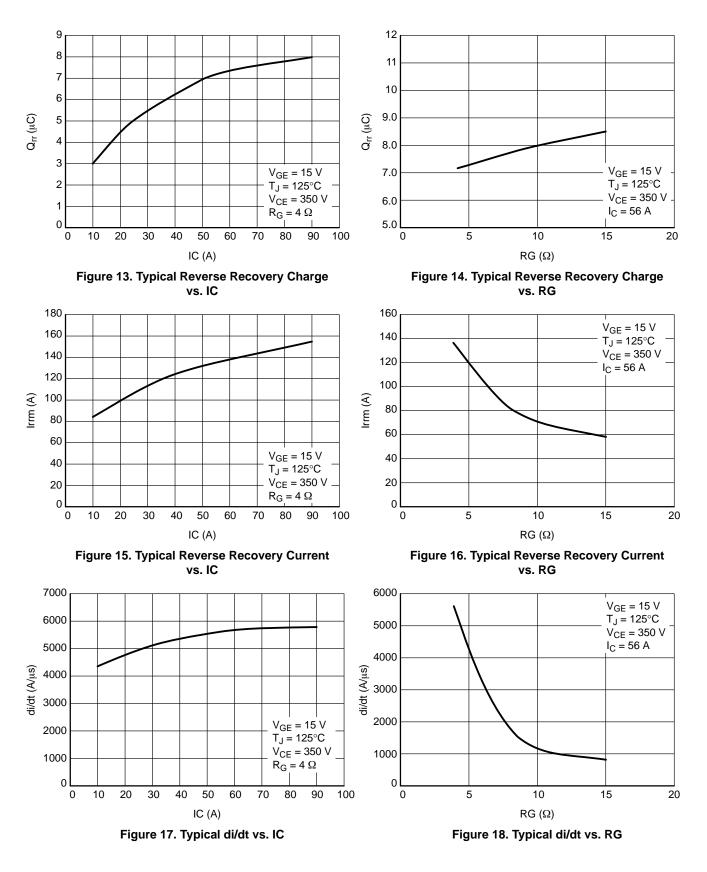
ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
NEUTRAL POINT CLAMP IGBT CHA	ARACTERISTICS			•		
Turn-on delay time	T _i = 25°C	t _{d(on)}	-	46	-	ns
Rise time	$V_{CE} = 350 \text{ V}, \text{ I}_{C} = 56 \text{ A}$	tr	_	16	-	
Turn-off delay time	V_{GE} = ±15 V, R _G = 4 Ω	t _{d(off)}	-	125	-	
Fall time	1	t _f	_	60	-	
Turn on switching loss	1	Eon	_	0.668	-	mJ
Turn off switching loss	1	E _{off}	-	0.76	-	
Turn–on delay time	T _j = 150°C	t _{d(on)}	_	48	-	ns
Rise time	$V_{CE} = 350 \text{ V}, \text{ I}_{C} = 56 \text{ A}$	tr	-	22	-	
Turn-off delay time	$V_{GE} = \pm 15 \text{ V}, \text{ R}_{G} = 4 \Omega$	t _{d(off)}	_	200	-	
Fall time	1	t _f	_	134	-	
Turn on switching loss	1	E _{on}	_	1.1	-	mJ
Turn off switching loss	1	E _{off}	_	2.5	-	
Input capacitance	V _{CE} =20 V. V _{GE} = 0 V. f = 10 KHz	Cies	_	9900	-	pF
Output capacitance	1	C _{oes}	_	270	-	
Reverse transfer capacitance	1	C _{res}	_	270	_	
Gate charge total	V_{CE} = 480 V, I _C = 75 A, V _{GE} = ±15 V	Qg	_	390	_	nC
Thermal Resistance, chip-to-heatsink	Thermal grease thickness \leq 50 μ m λ = 1 W/mK	R _{θJH}		1.35		°C/W
NEUTRAL POINT CLAMP DIODE CI	HARACTERISTICS			•		
Forward voltage	V _{GE} = 0 V, I _F = 60 A T _i = 25°C	V _F	-	1.7	2.0	V
	$V_{GE} = 0 \text{ V}, I_F = 60 \text{ A}, T_j = 150^{\circ}\text{C}$		_	1.8	-	
Reverse recovery time	$T_j = 25^{\circ}C$	t _{rr}	-	0.04	-	μs
Reverse recovery charge	$V_{CE} = 350 \text{ V}, I_C = 56 \text{ A}$	Q _{rr}	-	1.1	-	μC
Peak reverse recovery current	V_{GE} = ±15 V, R _G = 4 Ω	I _{rrm}	-	65	-	А
Peak rate of fall of recovery current		di/dt _{max}	-	6600	-	A/μs
Reverse recovery energy	1	Err	-	0.384	-	mJ
Reverse recovery time	$T_j = 150^{\circ}C$	t _{rr}	-	0.1	-	μs
Reverse recovery charge	$V_{CE} = 350 \text{ V}, I_C = 56 \text{ A}$	Q _{rr}	-	3.3	-	μC
Peak reverse recovery current	V_{GE} = ±15 V, R _G = 4 Ω	I _{rrm}	_	68	-	А
Peak rate of fall of recovery current	1	di/dt _{max}	_	1733	-	A/μs
Reverse recovery energy	1	Err	_	0.74	-	mJ
Thermal Resistance, chip-to-heatsink	Thermal grease thickness \leq 50 μm λ = 1 W/mK	$R_{ hetaJH}$		1.86		°C/W
THERMISTOR CHARACTERISTICS						
Normal resistance		R		22		kΩ
Nominal resistance	T = 100°C	R		1468		Ω
Deviation of R25		$\Delta R/R$	-5		5	%
Power dissipation		PD		200		mW
Power dissipation constant				2		mW/K
B-value	B(25/50), tol ±3%				3950	К
B-value	B(25/100), tol ±3%			1	3998	К
NTC reference				1	В	1

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.







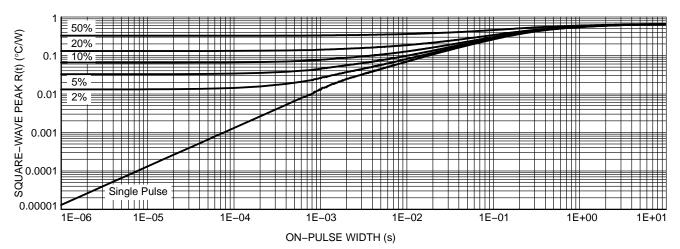


Figure 19. IGBT Transient Thermal Impedance

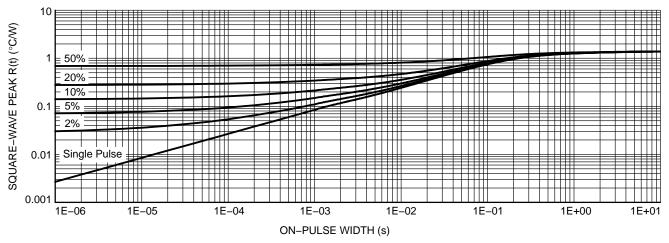
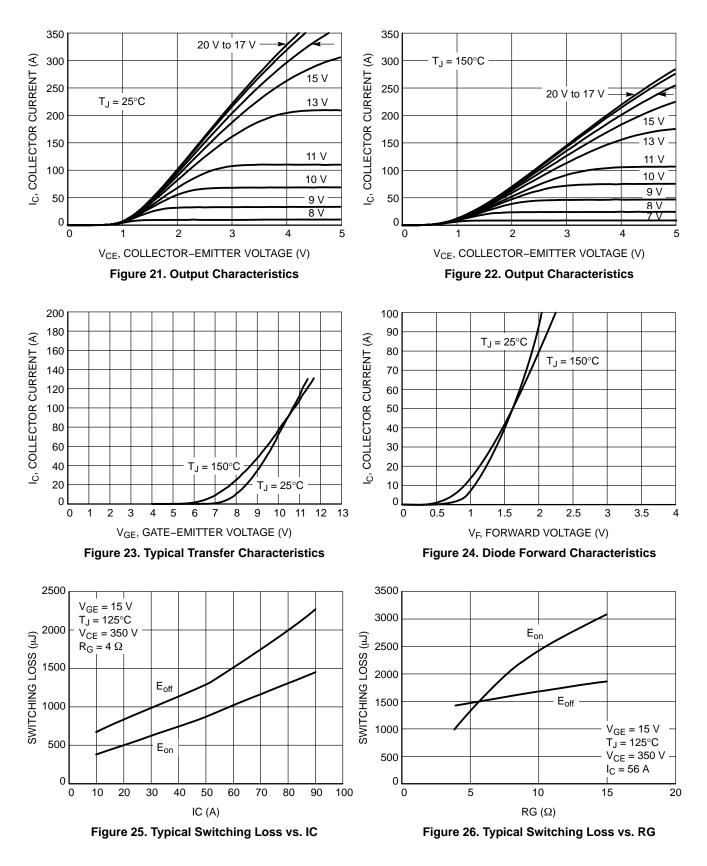
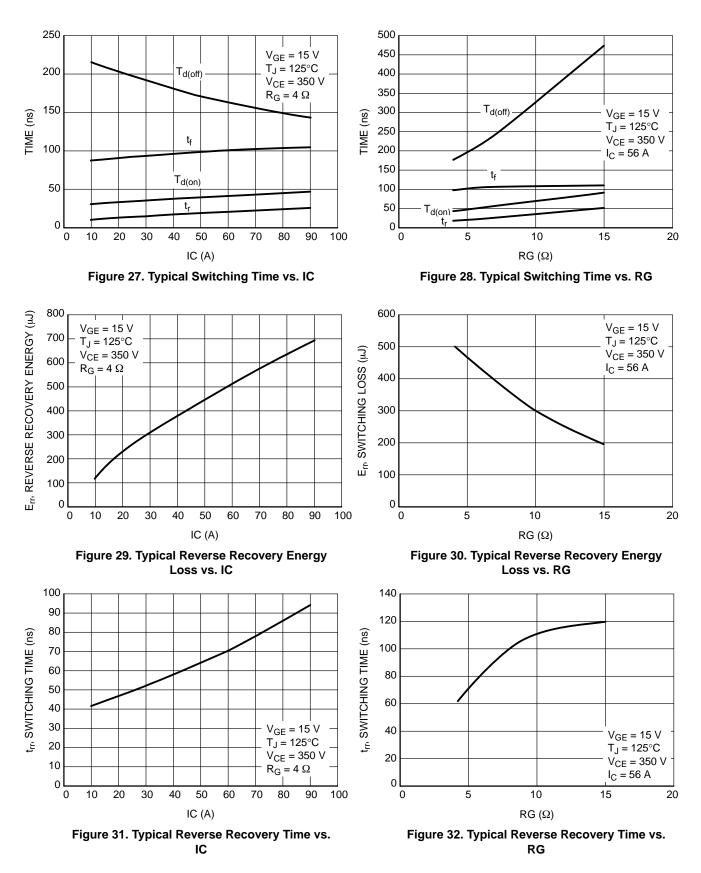
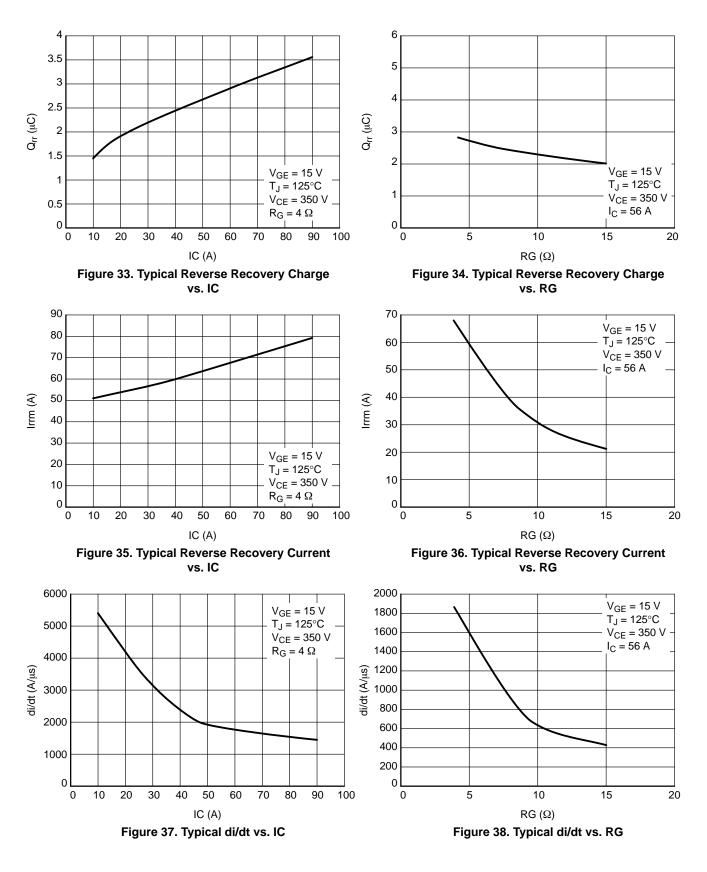


Figure 20. Diode Transient Thermal Impedance







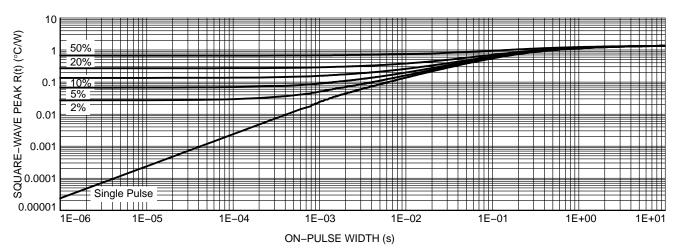


Figure 39. IGBT Transient Thermal Impedance

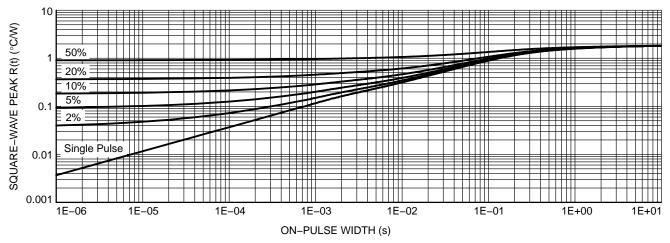
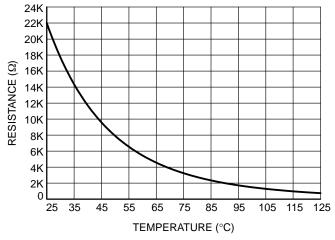


Figure 40. Diode Transient Thermal Impedance

THERMISTOR CHARACTERISTICS

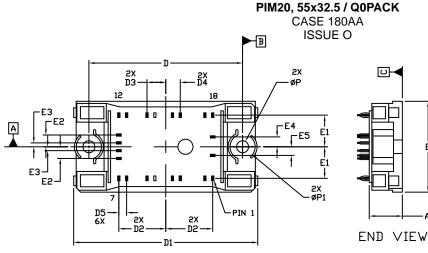




ORDERING INFORMATION

Orderable Part Number	Package	Shipping
NXH80T120L2Q0PG (Press Fit Pin)	Q0PACK – Case 180AA (Pb–Free and Halide–Free)	24 Units / Blister Tray
NXH80T120L2Q0SG (Solder Pin)	Q0PACK – Case 180AB (Pb–Free and Halide–Free)	24 Units / Blister Tray

PACKAGE DIMENSIONS



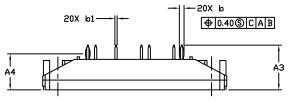
NOTES

- 1. DIMENSIONING AND TOLERANCING PER. ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS

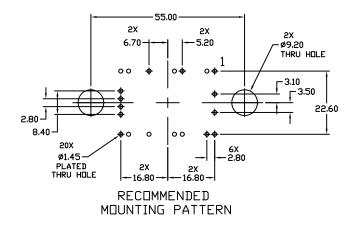
3. DIMENSIONS 6 AND 61 APPLY TO THE PLATED TERMINALS AND ARE MEASURED AT DIMENSION A4.

	MILLIMETERS	
DIM	MIN.	NDM.
Α	11.33	12.33
A3	15.50	16.50
Α4	12.88	B BSC
b	1.61	1.71
b1	0.75	0.85
D	54.80	55.20
D1	65.70	70.10
D2	16.80	D BSC
D3	6.70	D BSC
D4	5.20	D BSC
D5	2.80	D BSC
Е	32.30	32.70
E1	11.30	D BSC
E2	4.20	D BSC
E3	1.40	D BSC
E4	3.50 BSC	
E5	3.10	D BSC
Ρ	4.10	4.50
P1	8.50	9.50

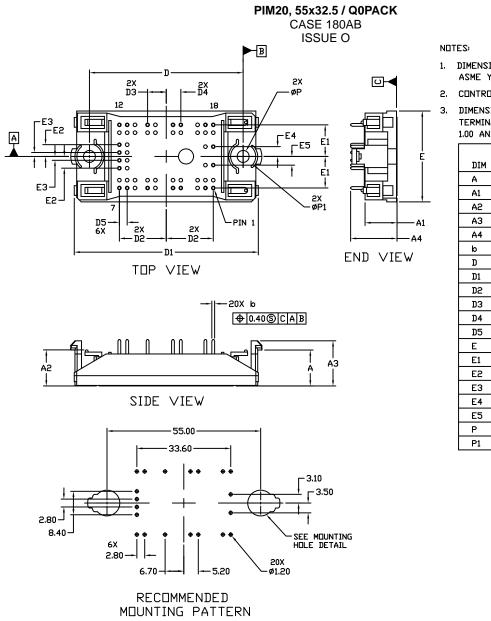




SIDE VIEW



PACKAGE DIMENSIONS



- DIMENSIONING AND TOLERANCING PER-ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS

DIMENSION & APPLIES TO THE PLATED TERMINALS AND ARE MEASURED BETWEEN 1.00 AND 3.00 FROM TERMINAL TIP.

	MILLIMETERS		
DIM	MIN.	NDM.	
Α	13.10	14.10	
A1	10.75	11.75	
A2	12.20	13.20	
A3	15.45	16.45	
A4	16.40	REF	
b	0.95	1.05	
D	54.80	55.20	
D1	65.70	70.10	
D2	16.80	BSC 3	
D3	6.70	BSC BSC	
D4	5.20	BSC BSC	
D5	2.80	BSC BSC	
Е	32.00	33.00	
E1	11.30) BSC	
E2	4.20) BSC	
E3	1.40	D BSC	
E4	3.50	D BSC	
E5	3.10	D BSC	
Р	4.10	4.50	
P1	8.50	9.50	

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